Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/506,302	ISHIHARA ET AL.
Examiner	Art Unit
Nguyen N. Hanh	2834

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Class	Subclass	Date	Examiner
310	261	10/17/2006	HN
310	216	10/17/2006	HN
310	217	10/17/2006	HN
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